

### **IGBT3** Chip

#### Features:

- 650V Trench & Field Stop technology
- low V<sub>CE(sat)</sub>
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling
- Qualified according to JEDEC for target applications

#### Recommended for:

power modules

### **Applications:**

drives



Chip Type	<b>V</b> <sub>CE</sub>	<i>I</i> cn <sup>1)</sup>	Die Size	Package
SIGC06T65E	650V	10A	2.4 x 2.38 mm <sup>2</sup>	sawn on foil

<sup>&</sup>lt;sup>1)</sup>nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

### **Mechanical Parameters**

Die size		2.4 x 2.38			
Emitter pad size (incl. gate pad)		See chip drawing	mm²		
Gate pad size		0.266 x 0.266	111111		
Area total		5.71			
Thickness		70	μm		
Wafer size		200	mm		
Max.possible chips per wafer		4879	4879		
Passivation frontside		Photoimide			
Pad metal		3200 nm AlSiCu			
Backside metal		Ni Ag –system			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		Al, <500μm			
Reject ink dot size		Ø 0.65mm; max 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C < 6 month			
	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or ine Humidity <25%RH, Temperature 17°C – 25°C, < 6 m			



### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, $T_{\rm vj}$ =25 °C	V <sub>CE</sub>	650	V
DC collector current, limited by $T_{\rm vj\;max}$	I <sub>C</sub>	1)	Α
Pulsed collector current, $t_p$ limited by $T_{vj \text{ max}}^{2}$	I <sub>c,puls</sub>	30	Α
Gate emitter voltage	V <sub>GE</sub>	±20	V
Operating junction temperature	$T_{vj}$	-40 <b>+</b> 175	°C
Short circuit data $^{2 (3)}$ $V_{\text{GE}} = 15\text{V}, V_{\text{CC}} = 360\text{V}, T_{\text{vj}} = 150^{\circ}\text{C}$	tsc	6	μs

<sup>1)</sup> depending on thermal properties of assembly

## Static Characteristics (tested on wafer), $T_{vj}$ =25 °C

Parameter	Symbol	Conditions	Value			Unit
- didiliotoi			min.	typ.	max.	0.111
Collector-Emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{\rm GE}$ =0V , $I_{\rm C}$ =2 mA	650			
Collector-Emitter saturation voltage	V <sub>CEsat</sub>	V <sub>GE</sub> =15V, I <sub>C</sub> =10A	1.03	1.45	1.87	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =150 $\mu {\rm A}$ , $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =650V , V <sub>GE</sub> =0V			0.6	μA
Gate-Emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V , V <sub>GE</sub> =20V			300	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

### **Electrical Characteristics** (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions	Value			Unit
raiailietei			min.	typ.	max.	Oilit
Collector-Emitter saturation voltage	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	V <sub>GE</sub> =15V, I <sub>C</sub> =10A,		thd		V
Collector-Entitler Saturation voltage	V <sub>CEsat</sub>	<i>T</i> <sub>vj</sub> =150 °C		tbd		V
Input capacitance	Cies	V <sub>CE</sub> =25V,		551		
		V <sub>GE</sub> =0V, <i>f</i> =1MHz				рF
Reverse transfer capacitance	C <sub>res</sub>	T <sub>vj</sub> =25 °C		17		<u> </u>

<sup>&</sup>lt;sup>2)</sup> not subject to production test - verified by design/characterization

<sup>&</sup>lt;sup>3)</sup> allowed number of short circuits: <1000; time between short circuits: >1s.



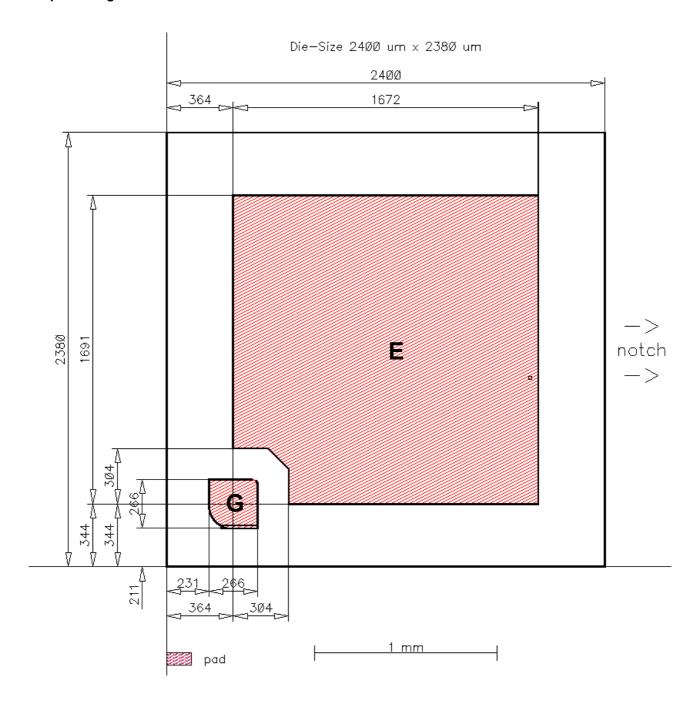
### **Further Electrical Characteristic**

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

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This chip data sheet refers to the device data sheet	tbd	tbd



## **Chip Drawing**



**E** = Emitter

**G** = Gate



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

#### **Revision History**

Version	Subjects (major changes since last revision)	Date

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